

Notice of References Cited	Application/Control No. 10/500,074	Applicant(s)/Patent Under Reexamination SAKAKI ET AL.	
	Examiner John P. Sheehan	Art Unit 1742	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,623,541 B2	09-2003	Sakaki et al.	75/232
*	B	US-2003/0041920 A1	03-2003	Hoshi et al.	148/122
*	C	US-6,399,150 B1	06-2002	Yoshimura et al.	427/242
*	D	US-2002/0036029 A1	03-2002	Kikugawa et al.	148/101
*	E	US-6,326,087 B1	12-2001	Nishiuchi et al.	428/611
*	F	US-US 20010030590A!	10-2001	Nishiuchi et al.	335/302
*	G	US-5,876,518 A	03-1999	Hasegawa et al.	148/302
*	H	US-4,966,668	10-1990	Veistinen, Mauri K.	427/528
*	I	US-4,837,114	06-1989	Hamada et al.	427/527
*	J	US-4,770,723	09-1988	Sagawa et al.	148/302
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 56-81908	07-1981	Japan	Okonogi et al.	---
	O	2000-40610	08-2000	Japan	Okabe	---
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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